

TTTC News

The TTTC website always lists the latest features and information for its visitors! To find out more, please visit the website at http://www.ieee-tttc.org/.

PAST TTTC EVENTS The IEEE International Test Conference (ITC 2018)

28 October–2 November 2018 Phoenix, AZ, USA http://www.itctestweek.org/about-itc/

The International Test Conference (ITC) is the world's premier venue dedicated to the electronic test of devices, boards, and systems-covering the complete cycle from design verification, designfor-test, design-for-manufacturing, silicon debug, manufacturing test, system test, diagnosis, reliability and failure analysis, and back to process and design improvement. At ITC, design, test, and yield professionals can confront challenges faced by the industry and learn how these challenges are being addressed by the combined efforts of academia, design tool, and equipment suppliers, designers, and test engineers. ITC, the cornerstone of the Test Week event, offers a wide variety of technical activities targeted at test and design theoreticians and practitioners, including formal paper sessions, tutorials, panel sessions, case studies, invited lectures, commercial exhibits and presentations, and a host of ancillary professional meetings.

UPCOMING TTTC EVENTS

The 22nd Design, Automation, and Test in Europe Conference 25–29 March 2019 Florence, Italy

https://www.date-conference.com/

Digital Object Identifier 10.1109/MDAT.2019.2898160 Date of current version: 11 April 2019. The 22nd Design, Automation, and Test in Europe (DATE) Conference and Exhibition is the main European event bringing together designers and design automation users, researchers, and vendors, as well as specialists in the hardware and software design, test, and manufacturing of electronic circuits and systems. DATE puts a strong emphasis on both technology and systems, covering ICs/SoCs, reconfigurable hardware and embedded systems, and embedded software.

The five-day event consists of a conference with plenary invited papers, regular papers, panels, hot-topic sessions, tutorials and workshops, two special focus days, and a track for executives. The scientific conference is complemented by a commercial exhibition showing the state of the art in design and test tools, methodologies, IP and design services, reconfigurable and other hardware platforms, embedded software, and (industrial) design experiences from different application domains, for example, automotive, wireless, telecom, and multimedia applications. The organization of user group meetings, fringe meetings, a university booth, a PhD forum, vendor presentations, and social events offers a wide variety of extra opportunities to meet and exchange information on relevant issues for the design and test community. Special space will also be allocated for EU-funded projects to show their results.

The IEEE VLSI Test Symposium

23–25 April 2019 Monterey, CA, USA http://tttc-vts.org/public_html/new/2019/

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, debug, and repair of microelectronic circuits and systems.

The VTS Program Committee invites original, unpublished paper submissions for VTS 2019. Proposals for the innovative practices and special sessions tracks are also invited. Paper submissions should be complete manuscripts, up to six pages (inclusive of figures, tables, and bibliography) in a standard IEEE two-column format; papers exceeding the page limit will be returned without review. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include author name(s) and affiliation(s) and the mailing address, phone number, and e-mail address of the contact author. A 50-word abstract and five keywords identifying the topic area are also required.

The 24th European Test Symposium

27–31 May 2019 Baden-Baden, Germany https://www.testgroup.polito.it/ets19/

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuits and system testing, reliability, security, and validation. In 2019, ETS will take place in the Congress Center in Baden-Baden. It is organized by the Karlsruhe Institute of Technology, Karlsruhe, Germany, which cosponsors the event jointly with the IEEE Council on Electronic Design Automation. In addition to scientific paper submissions, this year, ETS will also offer an embedded workshop dedicated to work in progress and case studies as well as a PhD forum. The special track on Emerging Test Strategies (ETS2) will again focus on upcoming problems and ideas in an industrial context. A Test Spring School will be organized in conjunction with ETS'19.

NEWSLETTER EDITOR'S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia, 1678, Cyprus; ttheocharides@ucy.ac.cy.

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